

AMENDMENTS TO THE SPECIFICATION

Please replace the paragraph bridging pages 108 and 109 with the following amended paragraph:

The isolation rate of external additives (silica fine particles and titanium oxide fine particles) was measured with ~~PT400~~PT1000 Particle Analyzer (a product of Yokogawa Electric Corporation). The details of measuring method of the isolation rate of external additives are disclosed in patent document 13 (JP-A-2002-202622). Describing the principle in brief, isolation rate is obtained by introducing toner particles into plasma, exciting the toner particle to emit light, and measuring the intensity and time of the emission. For example, toner particles to which external additive SiO₂ has been added are introduced into plasma, and the emission intensity of SiO₂ in the toner particles is measured. Assuming that the toner particle to which SiO₂ has been externally added is a spherical particle, the particle size of the spherical particle (equivalent particle size) is obtained from the emission intensity. Similarly to the case of the toner particle, the equivalent particle size of the liberated SiO₂ can be obtained from the emission intensity. However, since the emission intensity of the liberated SiO₂ is small, the equivalent particle size is small. Accordingly, the liberated external additive can be distinguished from the toner particles by comparing equivalent particle sizes. Therefore, the isolation rate of SiO₂ can be obtained according to the following equation (X), by obtaining all the detected number of external additive SiO₂, and taking the number of individuals having smaller equivalent particle size as the number of particles of the liberated external additive.